

## PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s):	Yip et al.	Examiner:	Rodriguez, Glenda P.
Application No.:	09/851,767	Group Art Unit:	2651
Filed:	May 9, 2001	Docket No.:	STL9663
Title:	Pattern-Based Defect Description Method		

COMMUNICATION

Sir:

In response to the Notice of Allowance and Issue Fee communication mailed April 26, 2005, please consider the following remarks.

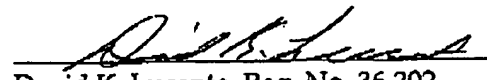
RemarksComments on Statement of Reasons for Allowance

The Applicant agrees with the Examiner's Statement of Reasons for Allowance to the extent that the claims of the present invention are patentable over the references in the record. The Applicant expressly traverses the Examiner's Statement of Reasons for Allowance to the extent that any comment is intended or has the effect of limiting a claim scope, explicitly or implicitly, by not reciting verbatim the respective claim language, or is intended or has the effect of limiting a claim scope by stating or implying that all the reasons for patentability are in any way fully enumerated.

Respectfully submitted,

Seagate Technology LLC  
(Assignee of the Entire Interest)

5/2/05  
Date

  
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